L Number	Hits	Search Text	DB	Time stamp
1	33	(synthesiz$3 synthesis) same (false near6 path)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/24 19:48
-	4131	(714/724,726,727,729).ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:15
-	644	((714/724,726,727,729).ccls.) and (boundary near2 scan)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:24
-	11	(((714/724,726,727,729).ccls.) and (boundary near2 scan)) and delay near4 chain	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:24
-	21	(((714/724,726,727,729).ccls.) and (boundary near2 scan)) and (delay near4 (chain measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:36
-	366	((714/724,726,727,729).ccls.) and (boundary near2 scan near4 (cell device buffer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:35
-	12	(((714/724,726,727,729).ccls.) and (boundary near2 scan near4 (cell device buffer))) and (delay near4 (chain measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:33
-	0	((((714/724,726,727,729).ccls.) and (boundary near2 scan near4 (cell device buffer))) and (delay near4 (chain measurement))) not ((((714/724,726,727,729).ccls.) and (boundary near2 scan)) and (delay near4 (chain measurement)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:26
-	9	((((714/724,726,727,729).ccls.) and (boundary near2 scan)) and (delay near4 (chain measurement))) not ((((714/724,726,727,729).ccls.) and (boundary near2 scan near4 (cell device buffer))) and (delay near4 (chain measurement)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:27
-	286	(((714/724,726,727,729).ccls.) and (boundary near2 scan near4 (cell device buffer))) and (bypass multiplex$2 MUX)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:33
-	109	((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multplex$2 mux))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:35
-	177	((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex$2 mux))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:36
-	7	(((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex$2 mux))) and (delay near4 (chain measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:37

-	12	(((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex$2 mux))) and (delay near4 (chain measur$5))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/24 15:01
-	5	((((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex$2 mux))) and (delay near4 (chain measur$5))) not ((((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex$2 mux))) and (delay near4 (chain measurement)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:18
-	0	5710779.pn	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:19
-	2	US-5710779$.did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 14:11
-	1		USPAT; US-PGPUB	2004/07/23 13:21
-	1		USPAT; US-PGPUB	2004/07/23 13:22
-	1		USPAT; US-PGPUB	2004/07/23 13:22
-	1		USPAT; US-PGPUB	2004/07/23 13:23
-	1		USPAT; US-PGPUB	2004/07/23 13:24
-	1		USPAT; US-PGPUB	2004/07/23 13:24
-	1		USPAT; US-PGPUB	2004/07/23 13:27
-	304	((714/724,726,727,729).ccls.) and ((scan near4 (cell device buffer)) same (bypass multiplex$2 mux))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/24 15:00
-	17	(((714/724,726,727,729).ccls.) and ((scan near4 (cell device buffer)) same (bypass multiplex$2 mux))) and (delay near4 (chain measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:48
-	202	(((714/724,726,727,729).ccls.) and ((scan near4 (cell device buffer)) same (bypass multiplex$2 mux))) and (TAP JTAG "1149" "test access port")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:48
-	32	((((714/724,726,727,729).ccls.) and ((scan near4 (cell device buffer)) same (bypass multiplex$2 mux))) and (TAP JTAG "1149" "test access port")) and (delay near4 (test chain measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:49
-	1	-0994361.did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 14:12
-	59	(boundary near2 scan) same (delay near4 (test$3 fault))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/24 15:02

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